# MOSFET – Power, N-Channel, SUPERFET<sup>®</sup> III, FRFET<sup>®</sup> 650 V, 30 A, 110 m $\Omega$

# **NVHL110N65S3F**

# Description

SUPERFET III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate.

Consequently, SUPERFET III MOSFET is very suitable for the various power system for miniaturization and higher efficiency.

SUPERFET III FRFET MOSFET's optimized reverse recovery performance of body diode can remove additional component and improve system reliability.

#### **Features**

- $700 \text{ V} @ \text{T}_{\text{J}} = 150^{\circ}\text{C}$
- Typ.  $R_{DS(on)} = 93 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ.  $Q_g = 58 \text{ nC}$ )
- Low Effective Output Capacitance (Typ. Coss(eff.) = 553 pF)
- 100% Avalanche Tested
- AEC-Q101 Qualified and PPAP Capable

## **Applications**

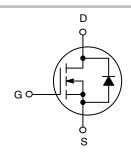
- Automotive On Board Charger HEV-EV
- Automotive DC/DC converter for HEV-EV



# ON Semiconductor®

#### www.onsemi.com

V <sub>DSS</sub>	R <sub>DS(on)</sub> MAX	I <sub>D</sub> MAX
650 V	110 mΩ @ 10 V	30 A

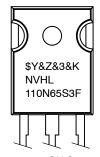


**N-Channel MOSFET** 



TO-247 LONG LEADS CASE 340CX

#### **MARKING DIAGRAM**



\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = Numeric Date Code

&K = Lot Code

NVHL110N65S3F = Specific Device Code

## **ORDERING INFORMATION**

See detailed ordering and shipping information on page 2 of this data sheet.

# ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25°C, Unless otherwise specified)

Symbol	Parameter	Value	Unit	
V <sub>DSS</sub>	Drain to Source Voltage		650	V
V <sub>GSS</sub>	Gate to Source Voltage	DC	±30	V
		AC (f > 1 Hz)	±30	V
I <sub>D</sub>	Drain Current	Continuous (T <sub>C</sub> = 25°C)	30	Α
		Continuous (T <sub>C</sub> = 100°C)	19.5	
I <sub>DM</sub>	Drain Current	Pulsed (Note 1)	69	Α
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)	380	mJ	
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)	2.4	mJ	
dv/dt	MOSFET dv/dt		100	V/ns
	Peak Diode Recovery dv/dt (Note 3)		50	
P <sub>D</sub>	Power Dissipation	(T <sub>C</sub> = 25°C)	240	W
		Derate Above 25°C	1.92	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 s		300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Repetitive rating: pulse-width limited by maximum junction temperature.

2.  $I_{AS} = 3.5 \text{ A}$ ,  $R_{G} = 25 \Omega$ , starting  $T_{J} = 25^{\circ}C$ .

3.  $I_{SD} \le 15 \text{ A}$ ,  $di/dt \le 200 \text{ A}/\mu\text{s}$ ,  $V_{DD} \le 400 \text{ V}$ , starting  $T_{J} = 25^{\circ}C$ .

## THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case, Max.	0.52	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient, Max.	40	

# PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Packing Method	Reel Size	Tape Width	Quantity
NVHL110N65S3F	NVHL110N65S3F	TO-247	Tube	N/A	N/A	30 Units

# **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
OFF CHARACT	ERISTICS					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 1 mA, T <sub>J</sub> = 25°C	650	_	-	V
		V <sub>GS</sub> = 0 V, I <sub>D</sub> = 10 mA, T <sub>J</sub> = 150°C	700	_	-	V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 20 mA, Referenced to 25°C	-	0.61	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 650 V, V <sub>GS</sub> = 0 V	_	_	10	μΑ
		V <sub>DS</sub> = 520 V, T <sub>C</sub> = 125°C	_	44	-	
I <sub>GSS</sub>	Gate to Body Leakage Current	V <sub>GS</sub> = ±30 V, V <sub>DS</sub> = 0 V	_	_	±100	nA
ON CHARACTE	RISTICS					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 0.74$ mA	3.0	_	5.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 15 A	_	93	110	mΩ
9FS	Forward Transconductance	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 15 A	_	17	-	S
DYNAMIC CHA	RACTERISTICS					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 400 V, V <sub>GS</sub> = 0 V, f = 1 MHz	-	2560	_	pF
C <sub>oss</sub>	Output Capacitance		-	50	-	pF
C <sub>oss(eff.)</sub>	Effective Output Capacitance	V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V	_	553	-	pF
C <sub>oss(er.)</sub>	Energy Related Output Capacitance	V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V	_	83	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10 V	V <sub>DS</sub> = 400 V, I <sub>D</sub> = 15 A, V <sub>GS</sub> = 10 V	-	58	-	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	(Note 4)	_	19	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge		_	23	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	2	-	Ω
SWITCHING CH	IARACTERISTICS					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 400 V, I <sub>D</sub> = 15 A,	-	29	-	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, R_g = 4.7 \Omega$ (Note 4)	-	32	-	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		_	61	-	ns
t <sub>f</sub>	Turn-Off Fall Time		_	16	-	ns
SOURCE-DRAI	N DIODE CHARACTERISTICS					
I <sub>S</sub>	Maximum Continuous Source to Drain Diode Forward Current		-	-	30	Α
I <sub>SM</sub>	Maximum Pulsed Source to Drain Diode Forward Current		_	-	69	Α
$V_{SD}$	Source to Drain Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 15 A	-	-	1.3	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 15 A,	_	94	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	dl <sub>F</sub> /dt = 100 A/μs	-	343	-	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Essentially independent of operating temperature typical characteristics.

#### TYPICAL CHARACTERISTICS

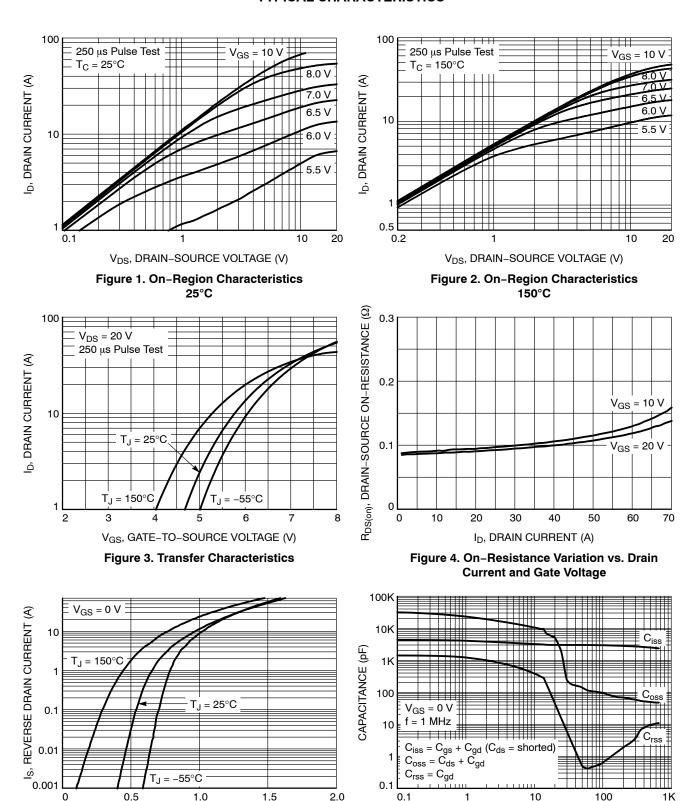


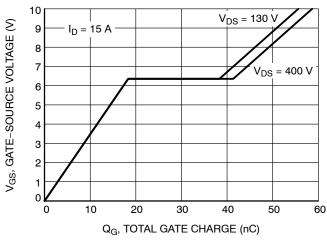
Figure 5. Body Diode Forward Voltage Variation vs. Source Current and Temperature

V<sub>SD</sub>, BODY DIODE FORWARD VOLTAGE (V)

V<sub>DS</sub>, DRAIN-TO-SOURCE VOLTAGE (V)

Figure 6. Capacitance Characteristics

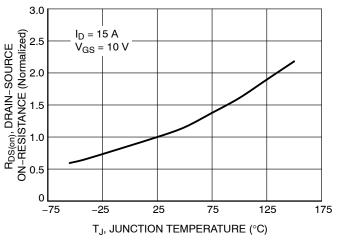
## **TYPICAL CHARACTERISTICS**



1.1 V<sub>GSS</sub> = 0 V I<sub>D</sub> = 10 mA V<sub>OSS</sub> DBAIN-1.1 V<sub>GSS</sub> DVAIN-1.1 V<sub>GSS</sub> DVAIN-1.1 V<sub>GSS</sub> DBAIN-1.1 V<sub>GSS</sub> DBA

Figure 7. Gate Charge Characteristics

Figure 8. Breakdown Voltage Variation vs. Temperature



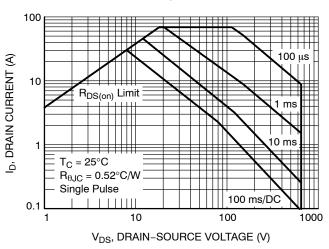
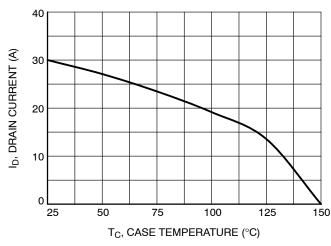


Figure 9. On-Resistance Variation vs. Temperature

Figure 10. Maximum Safe Operating Area



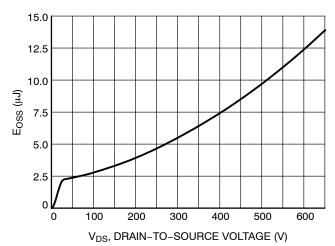


Figure 11. Maximum Drain Current vs. Case Temperature

Figure 12. E<sub>OSS</sub> vs. Drain-to-Source Voltage

# **TYPICAL CHARACTERISTICS**

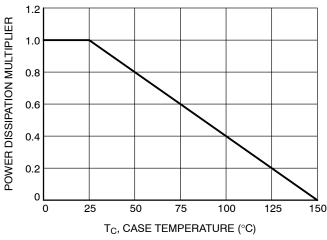


Figure 13. Normalized Power Dissipation vs. Case Temperature

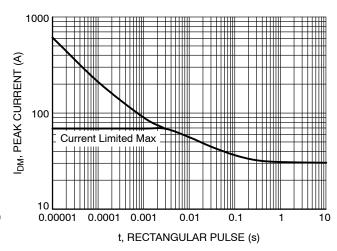


Figure 14. Peak Current Capability

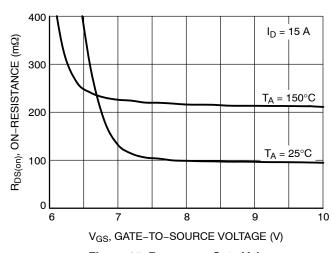


Figure 15. R<sub>DS(on)</sub> vs. Gate Voltage

0.0001

0.001

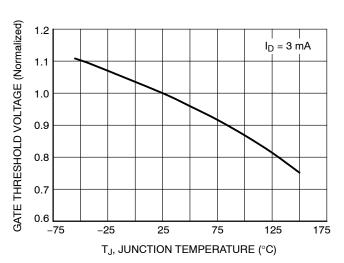
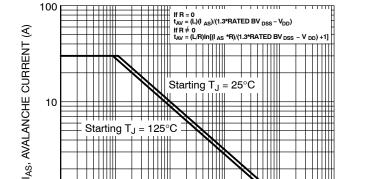


Figure 16. Normalized Gate Threshold Voltage vs. Temperature

10



 $t_{\text{AV}}\text{, TIME IN AVALANCHE (ms)}$  NOTE: Refer to Application Notes AN7514 and AN7515

0.01

Figure 17. Unclamped Inductive Switching Capability

0.1

# **TYPICAL CHARACTERISTICS**

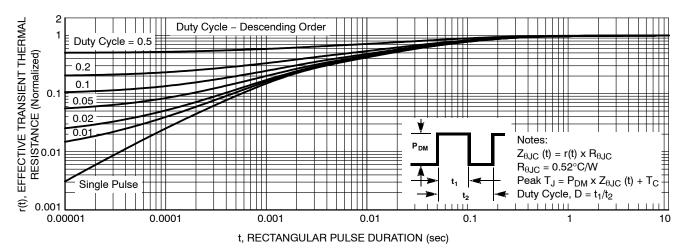


Figure 18. Transient Thermal Response

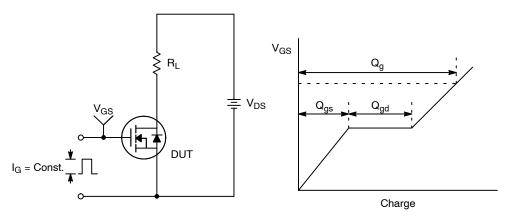


Figure 19. Gate Charge Test Circuit & Waveform

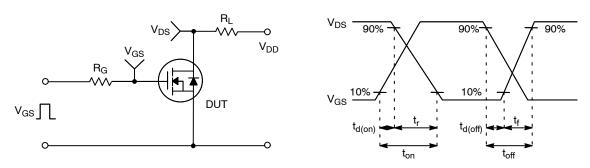


Figure 20. Resistive Switching Test Circuit & Waveforms

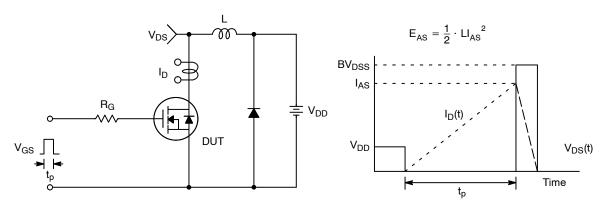


Figure 21. Unclamped Inductive Switching Test Circuit & Waveforms

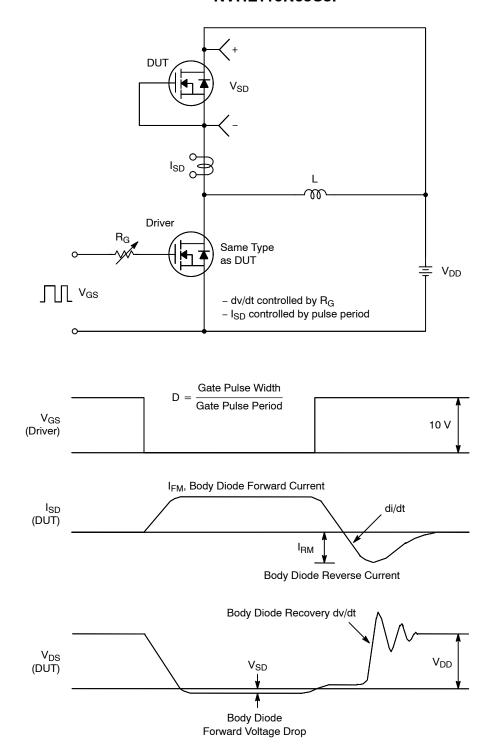
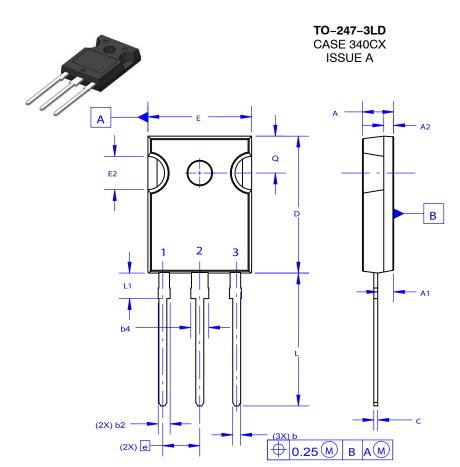


Figure 22. Peak Diode Recovery dv/dt Test Circuit & Waveforms

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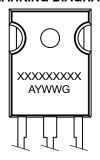
**DATE 06 JUL 2020** 



NOTES: UNLESS OTHERWISE SPECIFIED.

- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DRAWING CONFORMS TO ASME Y14.5 2009.
- D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
- E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

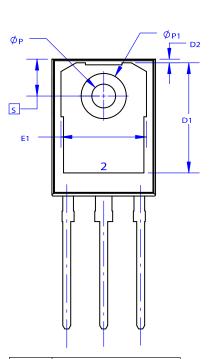
# GENERIC MARKING DIAGRAM\*



XXXXX = Specific Device Code A = Assembly Location

Y = Year WW = Work Week G = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " •", may or may not be present. Some products may not follow the Generic Marking.



DIM	MILLIMETERS				
DIM	MIN	NOM	MAX		
Α	4.58	4.70	4.82		
<b>A</b> 1	2.20	2.40	2.60		
A2	1.40	1.50	1.60		
D	20.32	20.57	20.82		
E	15.37	15.62	15.87		
E2	4.96	5.08	5.20		
е	~	5.56	~		
L	19.75	20.00	20.25		
L1	3.69	3.81	3.93		
ØΡ	3.51	3.58	3.65		
Q	5.34	5.46	5.58		
S	5.34	5.46	5.58		
b	1.17	1.26	1.35		
b2	1.53	1.65	1.77		
b4	2.42	2.54	2.66		
С	0.51	0.61	0.71		
D1	13.08	~	~		
D2	0.51	0.93	1.35		
E1	12.81	~	~		
ØP1	6.60	6.80	7.00		

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